Application/Control No. Applicant(s)/Patent Under Reexamination 10/026,061 COHEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Yasin M. Barqadle 2153 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,269,351 07-2001 Black, Christopher Lee Α 706/15 * US-6,249,781 06-2001 Sutton, Richard S. В 706/25 * US-2003/0018494 01-2003 Bronstein et al. С 705/2 US-D US-Ę US-F US-G USн USı US-J USκ US-L US-М

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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<u> </u>		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	Eric et al, "In Proceedings of the Thirteen Annual Conference on Uncertainty in Artificial Intelligence (UAI-97), pages 3-13, Providence, Rhode Island, august 1-3, 1997					
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.